# N-channel TrenchMOS logic level FET

Rev. 01 — 14 October 2008

**Preliminary data sheet** 

# 1. Product profile

### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in industrial and communications applications.

#### 1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

#### 1.3 Applications

- Class-D amplifiers
- DC-to-DC converters

- Motor control
- Server power supplies

#### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$		-	-	30	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u> ;	<u>[1]</u>	-	-	100	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	74	W
Dynamic	characteristics						
$Q_{GD}$	gate-drain charge	$V_{GS}$ = 4.5 V; $I_D$ = 10 A; $V_{DS}$ = 12 V; see <u>Figure 14</u> ; see <u>Figure 15</u>		-	5	-	nC
Static ch	aracteristics						
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure } 12}{}$		-	2.2	3.5	mΩ

<sup>[1]</sup> Continuous current is limited by package.



## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol		
1	S	source				
2	S	source	mb	D		
3	S	source		$G \longrightarrow \overline{A}$		
4	G	gate	Qj			
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S		
			SOT669 (LFPAK)			

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN3R5-30YL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

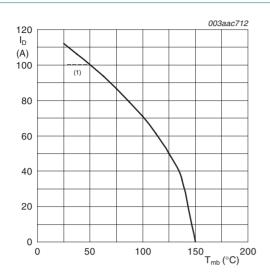
# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

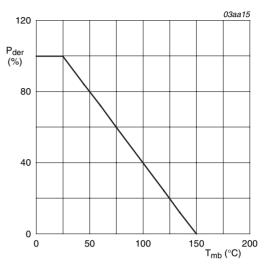
Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C		-	30	V
$V_{DGR}$	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
$V_{GS}$	gate-source voltage			-20	20	V
$I_D$	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 1}};$	[1]	-	79	Α
		V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u> ;	[1]	-	100	Α
$I_{DM}$	peak drain current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$ ; see <u>Figure 3</u>		-	447	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	74	W
T <sub>stg</sub>	storage temperature			-55	150	°C
Tj	junction temperature			-55	150	°C
Source-dr	ain diode					
Is	source current	T <sub>mb</sub> = 25 °C;	[1]	-	100	Α
I <sub>SM</sub>	peak source current	t <sub>p</sub> ≤ 10 μs; pulsed; T <sub>mb</sub> = 25 °C		-	447	Α
Avalanche	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 100 A; $V_{sup} \le$ 30 V; $R_{GS}$ = 50 Ω; unclamped		-	54	mJ

<sup>[1]</sup> Continuous current is limited by package.



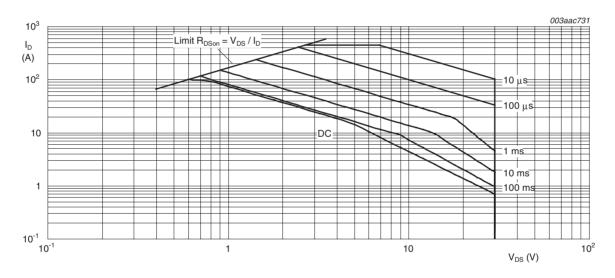
 $V_{GS} \! \geq \! 10 \, V \label{eq:VGS}$  (1) Capped at 100 A due to package.

Fig 1. Continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$  is single pulse (1) Capped at 100 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

### 5. Thermal characteristics

#### Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.6	1.68	K/W

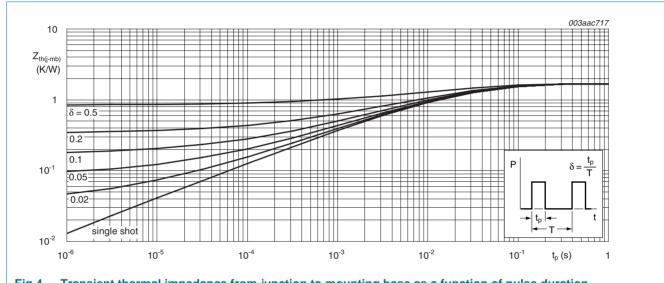


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

### 6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 25 °C; see Figure 10; see Figure 11	1.3	1.7	2.15	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 150$ °C; see Figure 10	0.65	-	-	V
		$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = -55 °C; see Figure 10	-	-	2.45	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C}; \text{ see}$ Figure 12	-	3.18	5.6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C}; \text{ see}$ Figure 13	-	-	6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}; \text{ see}$ Figure 12	-	2.2	3.5	mΩ
$R_{G}$	gate resistance	f = 1 MHz	-	0.53	-	Ω
Dynamic	characteristics					
$Q_{G(tot)}$	total gate charge	$I_D$ = 10 A; $V_{DS}$ = 12 V; $V_{GS}$ = 4.5 V; see Figure 14; see Figure 15	-	19	-	nC
		$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	37	-	nC
		$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 10 \text{ V}$ ; see Figure 14; see Figure 15	-	41	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 4.5 \text{ V}$ ; see	-	6	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate-source charge	Figure 14; see Figure 15	-	4	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate-source charge		-	2	-	nC
$Q_{GD}$	gate-drain charge		-	5	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	V <sub>DS</sub> = 12 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	2.4	-	V
C <sub>iss</sub>	input capacitance	V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 0 V; f = 1 MHz;	-	2458	-	рF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 16</u>	-	532	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	252	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 12 V; $R_L$ = 0.5 $\Omega$ ; $V_{GS}$ = 4.5 V;	-	33	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 4.7 \Omega$	-	50	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	45	-	ns
t <sub>f</sub>	fall time		-	18	-	ns

3

2.8

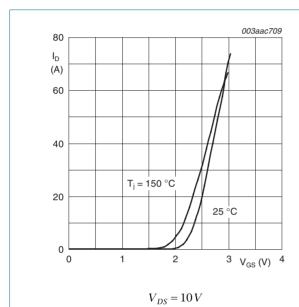
2.6

2.4

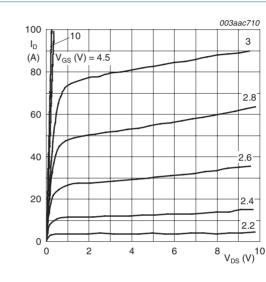
2.2

Characteristics ... continued Table 6.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 17	-	0.88	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$	-	[tbd]	37	ns
Q <sub>r</sub>	recovered charge	$V_{DS} = 20 \text{ V}$	-	[tbd]	31	nC

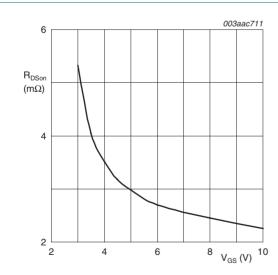


Transfer characteristics: drain current as a function of gate-source voltage; typical values



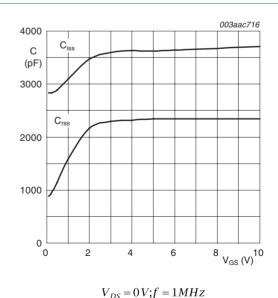
 $T_i = 25 \,^{\circ}C; t_p = 300 \,\mu s$ 

Output characteristics: drain current as a Fig 6. function of drain-source voltage; typical values



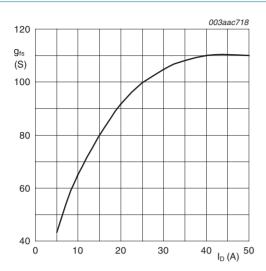
Drain-source on-state resistance as a function Fig 7. of gate-source voltage; typical values

 $T_i = 25 \,^{\circ}C; I_D = 15A$ 



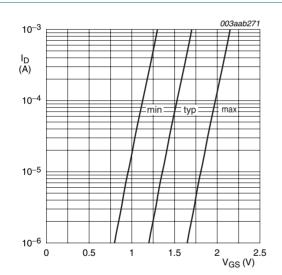
Input and reverse transfer capacitances as a Fig 8.

function of gate-source voltage; typical values



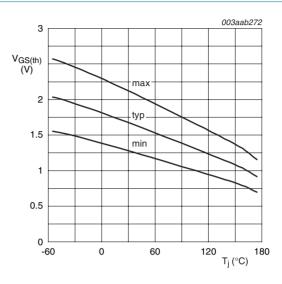
$$T_i = 25 \,^{\circ}C; V_{DS} = 15 \, V$$

Fig 9. Forward transconductance as a function of drain current; typical values



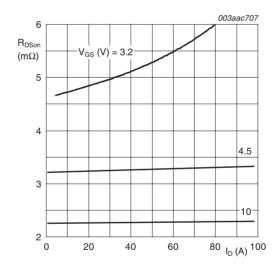
 $T_j = 25 \,^{\circ}C; V_{DS} = 5 \, V$ 

Fig 11. Sub-threshold drain current as a function of gate-source voltage



$$I_D = 1 \, mA; V_{DS} = V_{GS}$$

Fig 10. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25 \,{}^{\circ}C; t_p = 300 \,\mu s$ 

Fig 12. Drain-source on-state resistance as a function of drain current; typical values

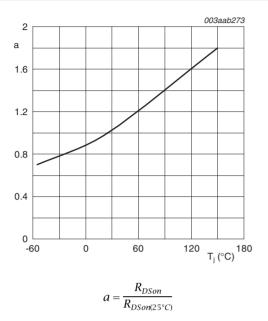


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

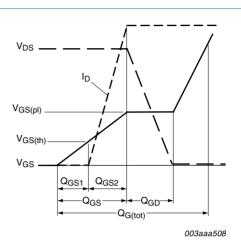


Fig 14. Gate charge waveform definitions

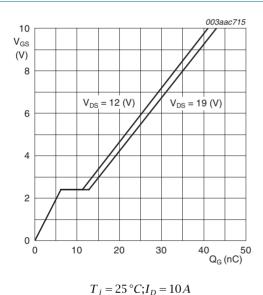
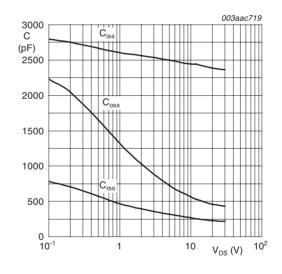


Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$ 

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

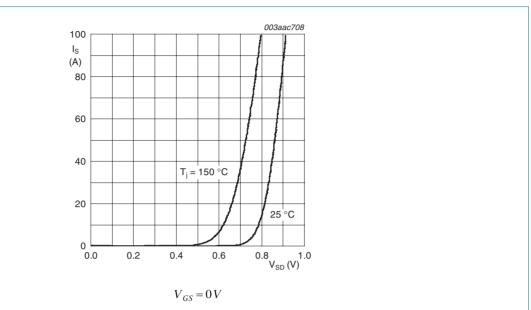
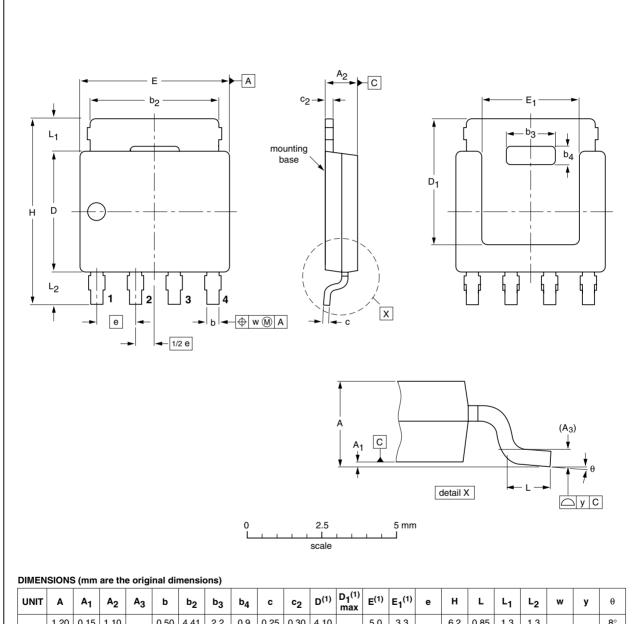


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

## Package outline

### Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 



UNIT	A	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b	b <sub>2</sub>	b <sub>3</sub>	b <sub>4</sub>	С	c <sub>2</sub>	D <sup>(1)</sup>	D <sub>1</sub> <sup>(1)</sup> max	E <sup>(1)</sup>	E <sub>1</sub> <sup>(1)</sup>	е	Н	L	L <sub>1</sub>	L <sub>2</sub>	w	у	θ
mm	1.20	0.15	1.10	0.25	0.50	4.41	2.2	0.9	0.25	0.30	4.10	4.20	5.0	3.3	1.27	6.2	0.85	1.3	1.3	0.25	0.1	8°
	1.01	0.00	0.95		0.35	3.62	2.0	0.7	0.19	0.24	3.80		4.8	3.1		5.8	0.40	0.8	8.0			0°

#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT669		MO-235			<del>04-10-13</del> 06-03-16

Fig 18. Package outline SOT669 (LFPAK)



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N-channel TrenchMOS logic level FET

# 8. Revision history

#### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN3R5-30YL_1	20081014	Preliminary data sheet	-	-

#### N-channel TrenchMOS logic level FET

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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### N-channel TrenchMOS logic level FET

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